



TGF2965-SM

5 W, 32 V, 0.03–3 GHz, GaN RF Input-Matched Transistor

General Description

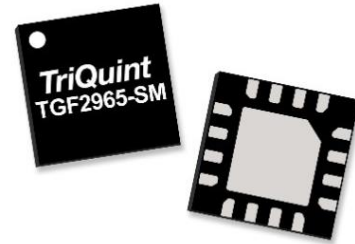
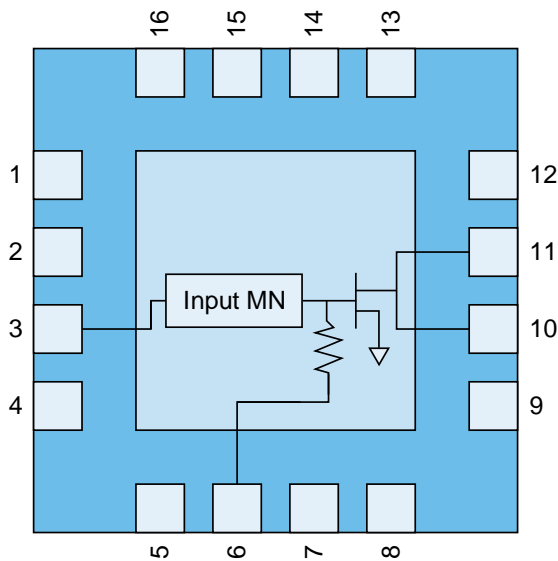
The Qorvo TGF2965-SM is a 6 W (P_{3dB}), 50 Ω -input matched discrete GaN on SiC HEMT which operates from 0.03 to 3.0 GHz. The integrated input matching network enables wideband gain and power performance, while the output can be matched on board to optimize power and efficiency for any region within the band.

The device is housed in an industry-standard 3 x 3 mm surface mount QFN package.

Lead-free and ROHS compliant

Evaluation boards are available upon request.

Functional Block Diagram



Product Features

- Frequency: 0.03 to 3.0 GHz
 - Output Power (P_{3dB})¹: 6.0 W
 - Linear Gain¹: 18 dB
 - Typical $DEFF_{3dB}$ ¹: 65%
 - Operating Voltage: 32 V
 - Low thermal resistance package
 - CW and Pulse capable
 - 3 x 3 mm package
- ¹ At 2 GHz

Applications

- Military Radar
- Civilian Radar
- Land Mobile and Military Radio Communications
- Test Instrumentation
- Wideband and Narrowband Amplifiers
- Jammers

Ordering Information

| Part | Description |
|----------------|----------------------------------|
| 1123170 | TGF2965-SM 100 pc MOQ |
| 1123185 | TGF2965-SM EVB |
| TGF2965-SMTR13 | TGF2965-SM Tape/Reel 2500 pc MOQ |

Absolute Maximum Ratings

| Parameter | Value/Range |
|---|-------------|
| Breakdown Voltage (V_{D0}) | 100 V min. |
| Gate Voltage Range (V_G) | -7 to +2 V |
| Drain Current (I_D) | 0.6 A |
| Gate Current (I_G) | See page 4. |
| Power Dissipation (P_D) | 7.5 W |
| RF Input Power, CW, $T = 25\text{ }^\circ\text{C}$ (P_{IN}) | 30 dBm |

Operation of this device outside the parameter ranges given above may cause permanent damage. These are stress ratings only, and functional operation of the device at these conditions is not implied.

Recommended Operating Conditions

| Parameter ¹ | Value/Range |
|---|---------------|
| Drain Voltage (V_D) | 32 V (Typ.) |
| Drain Quiescent Current (I_{DQ}) | 25 mA (Typ.) |
| Peak Drain Current (I_D) | 326 mA (Typ.) |
| Gate Voltage (V_G) | -2.7 V (Typ.) |
| Power Dissipation, CW (P_D) | 7.05 W (Max) |
| Power Dissipation, Pulse (P_D) ² | 9.1 W (Max) |

¹Electrical specifications are measured at specified test conditions. Specifications are not guaranteed over all recommended operating conditions.

²100uS Pulse Width, 20% Duty Cycle

RF Characterization–Load Pull Performance

Test conditions unless otherwise noted: $T_A = 25\text{ }^\circ\text{C}$, $V_D = 32\text{ V}$, $I_{DQ} = 30\text{ mA}$, Pulse: 100 uS Pulse Width, 20% Duty Cycle

| Symbol | Parameter | Typical | | | | | Units |
|--------------|---|---------|------|------|------|------|-------|
| F | Frequency | 1 | 1.5 | 2 | 2.5 | 3 | GHz |
| G_{LIN} | Linear Gain, Power Tuned | 17.3 | 17.4 | 18.2 | 17.8 | 16.9 | dB |
| P_{3dB} | Output Power at 3 dB Gain Compression, Power Tuned | 37.8 | 37.7 | 37.8 | 38.1 | 38.3 | dBm |
| $DEFF_{3dB}$ | Drain Efficiency at 3 dB Gain Compression, Efficiency Tuned | 76.0 | 62.7 | 65.2 | 65.4 | 71.9 | % |
| G_{3dB} | Gain at 3 dB Compression, Power Tuned | 14.3 | 14.4 | 15.2 | 14.8 | 13.9 | dB |

RF Characterization–0.03–3 GHz EVB Performance at 2.5 GHz–Pulsed

Test conditions unless otherwise noted: $T_A = 25\text{ }^\circ\text{C}$, $V_D = 32\text{ V}$, $I_{DQ} = 30\text{ mA}$, Pulse: 100 uS Pulse Width, 20% Duty Cycle

| Symbol | Parameter | Min | Typical | Max | Units |
|------------|---|-----|---------|-----|-------|
| G_{LIN} | Linear Gain | | 17.1 | | dB |
| P_{3dB} | Output Power at 3 dB Gain Compression | | 5.0 | | W |
| DE_{3dB} | Drain Efficiency at 3 dB Gain Compression | | 50.6 | | % |
| G_{3dB} | Gain at 3 dB Compression | | 14.1 | | dB |

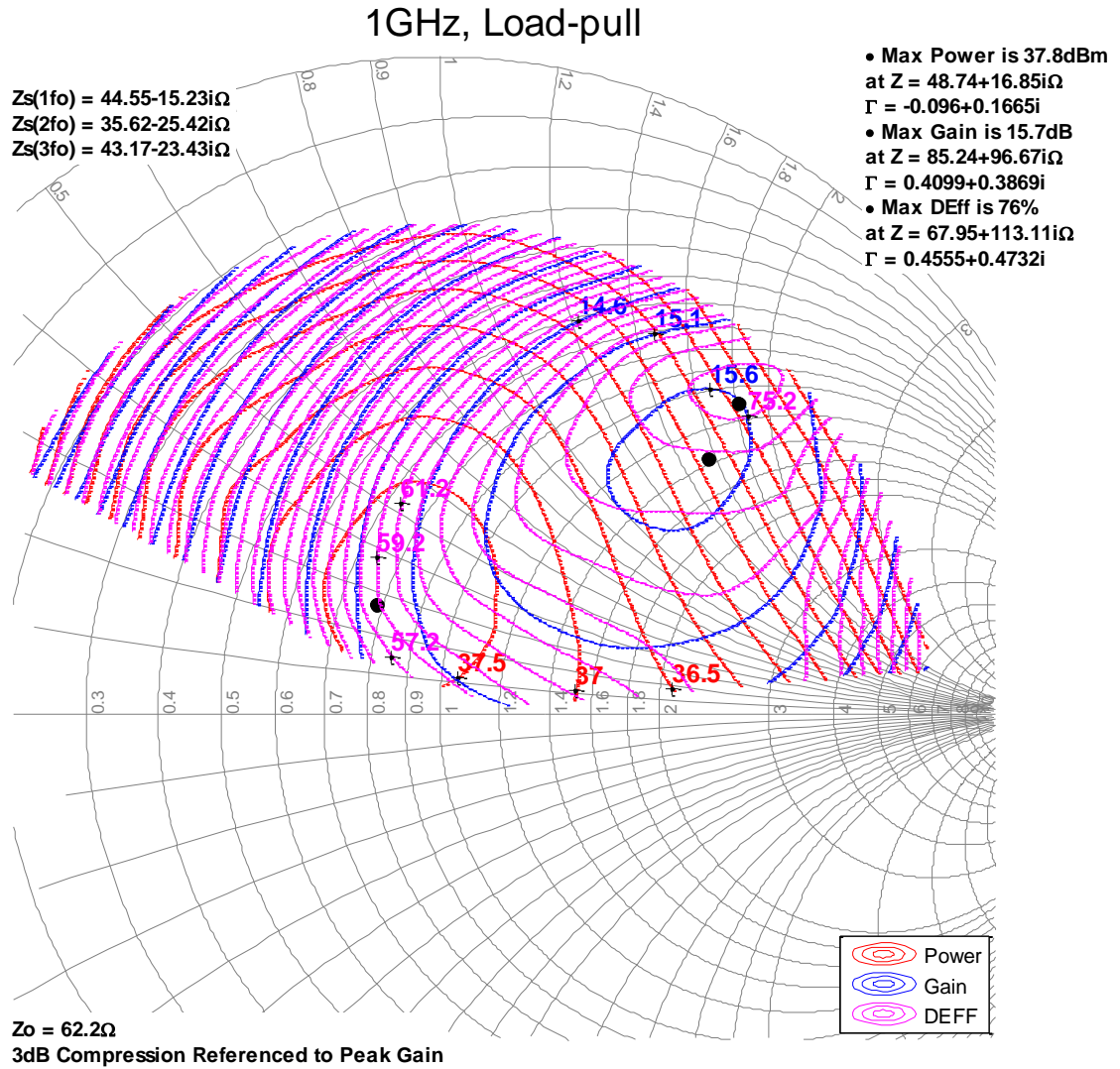
RF Characterization–Mismatch Ruggedness at 1, 2 and 3 GHz

Test conditions unless otherwise noted: $T_A = 25\text{ }^\circ\text{C}$, $V_D = 28\text{ V}$, $I_{DQ} = 30\text{ mA}$, Pulse: 100 uS Pulse Width, 20% Duty Cycle
Driving input power is determined at pulsed compression under matched condition at EVB output connector.

| Symbol | Parameter | dB Compression | Typical |
|--------|-------------------------------|----------------|---------|
| VSWR | Impedance Mismatch Ruggedness | 3 | 10:1 |
| VSWR | Impedance Mismatch Ruggedness | 8 | 2:1 |

Load Pull Smith Charts ^{1,2}

RF performance that the device typically exhibits when placed in the specified impedance environment. The impedances are not the impedances of the device, they are the impedances presented to the device via an RF circuit or load-pull system. The impedances listed follow an optimized trajectory to maintain high power and high efficiency.

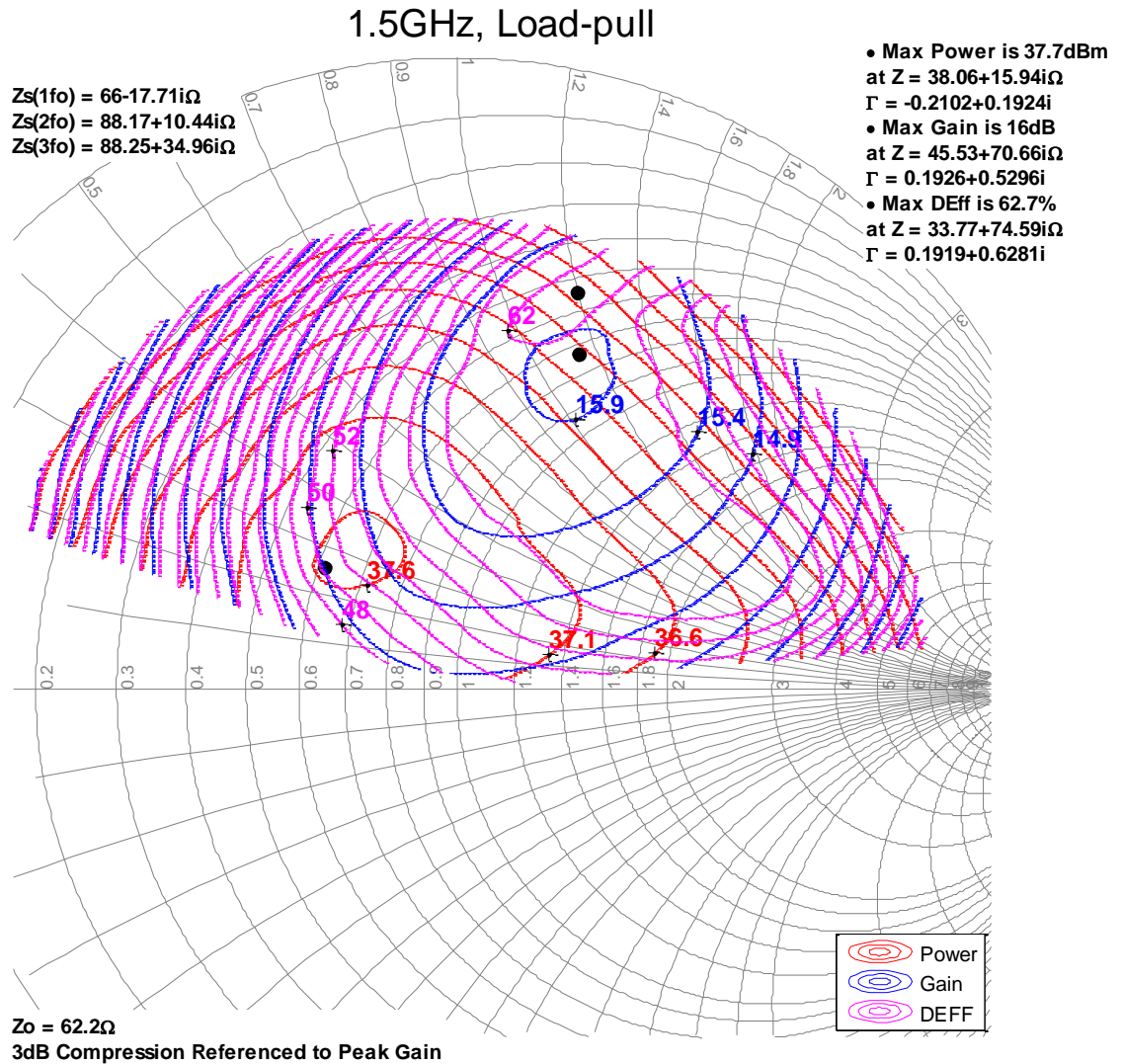


Notes:

1. 32 V, 30 mA, Pulsed signal with 100 uS pulse width and 20% duty cycle. 3 dB compression referenced to peak gain.
2. See page 18 for load pull and source pull reference planes.

Load Pull Smith Charts ^{1, 2}

RF performance that the device typically exhibits when placed in the specified impedance environment. The impedances are not the impedances of the device, they are the impedances presented to the device via an RF circuit or load-pull system. The impedances listed follow an optimized trajectory to maintain high power and high efficiency.

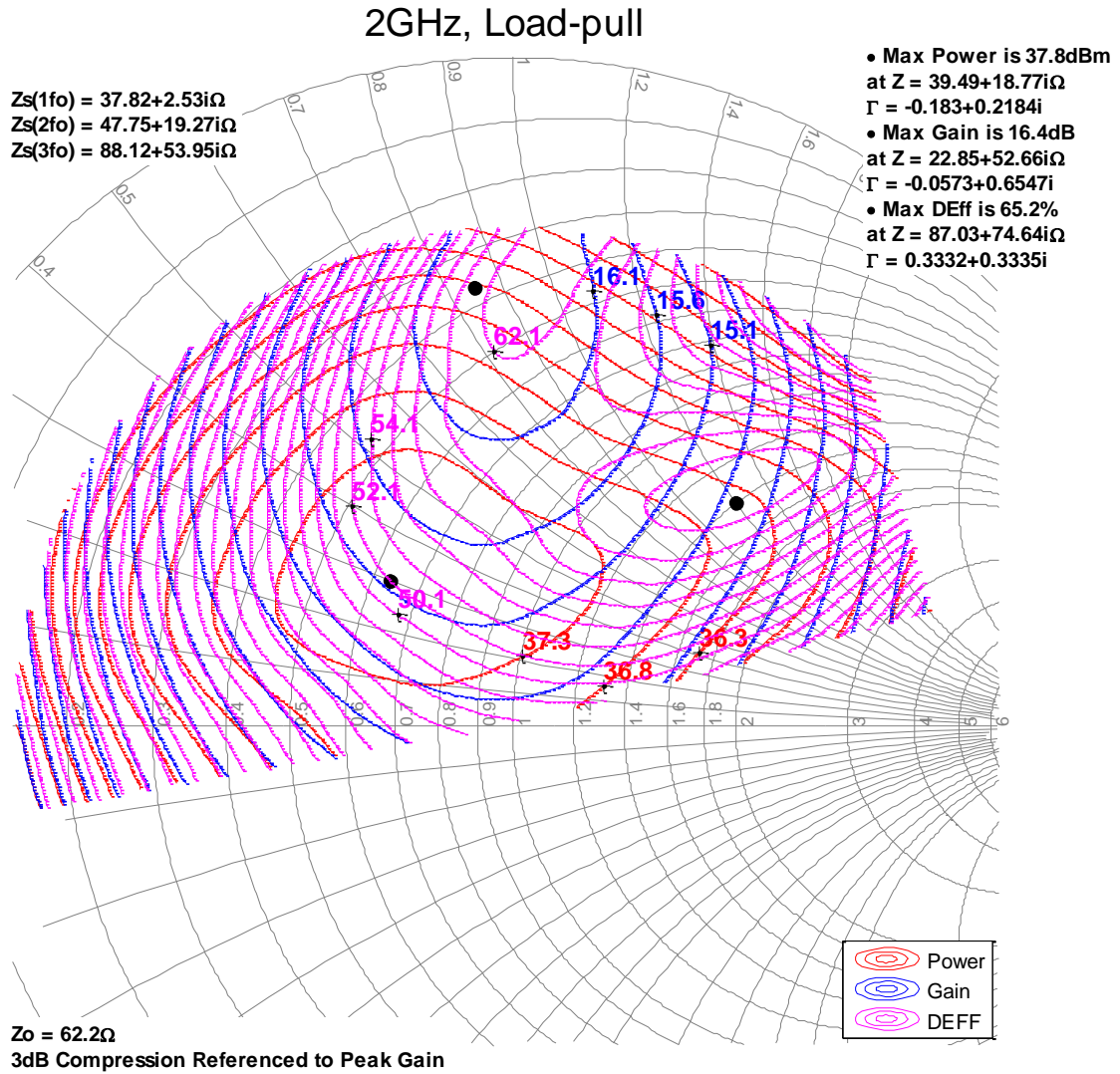


Notes:

1. 32 V, 30 mA, Pulsed signal with 100 uS pulse width and 20% duty cycle. 3 dB compression referenced to peak gain.
2. See page 18 for load pull and source pull reference planes.

Load Pull Smith Charts ^{1, 2}

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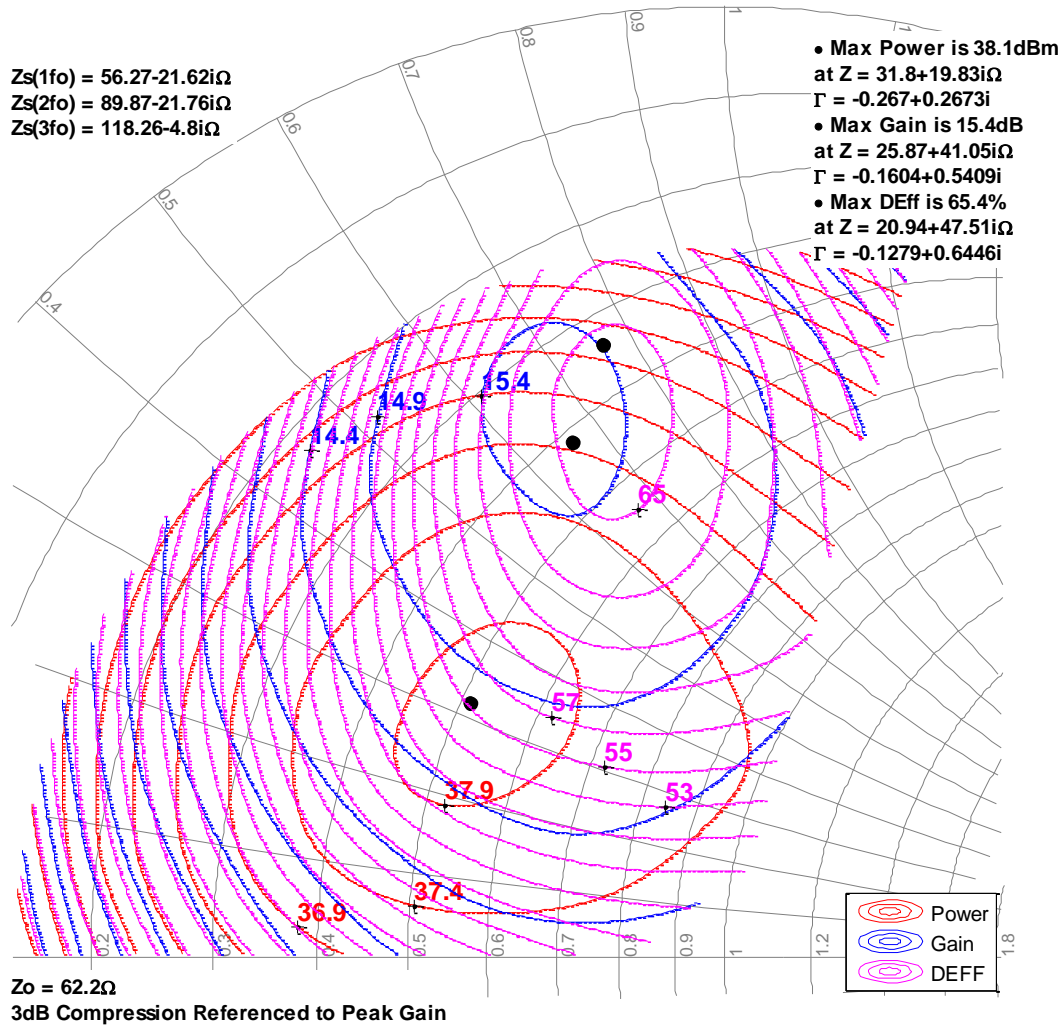
Notes:

1. 32 V, 30 mA, Pulsed signal with 100 uS pulse width and 20% duty cycle. 3 dB compression referenced to peak gain.
2. See page 18 for load pull and source pull reference planes.

Load Pull Smith Charts ^{1, 2}

RF performance that the device typically exhibits when placed in the specified impedance environment. The impedances are not the impedances of the device, they are the impedances presented to the device via an RF circuit or load-pull system. The impedances listed follow an optimized trajectory to maintain high power and high efficiency.

2.5GHz, Load-pull



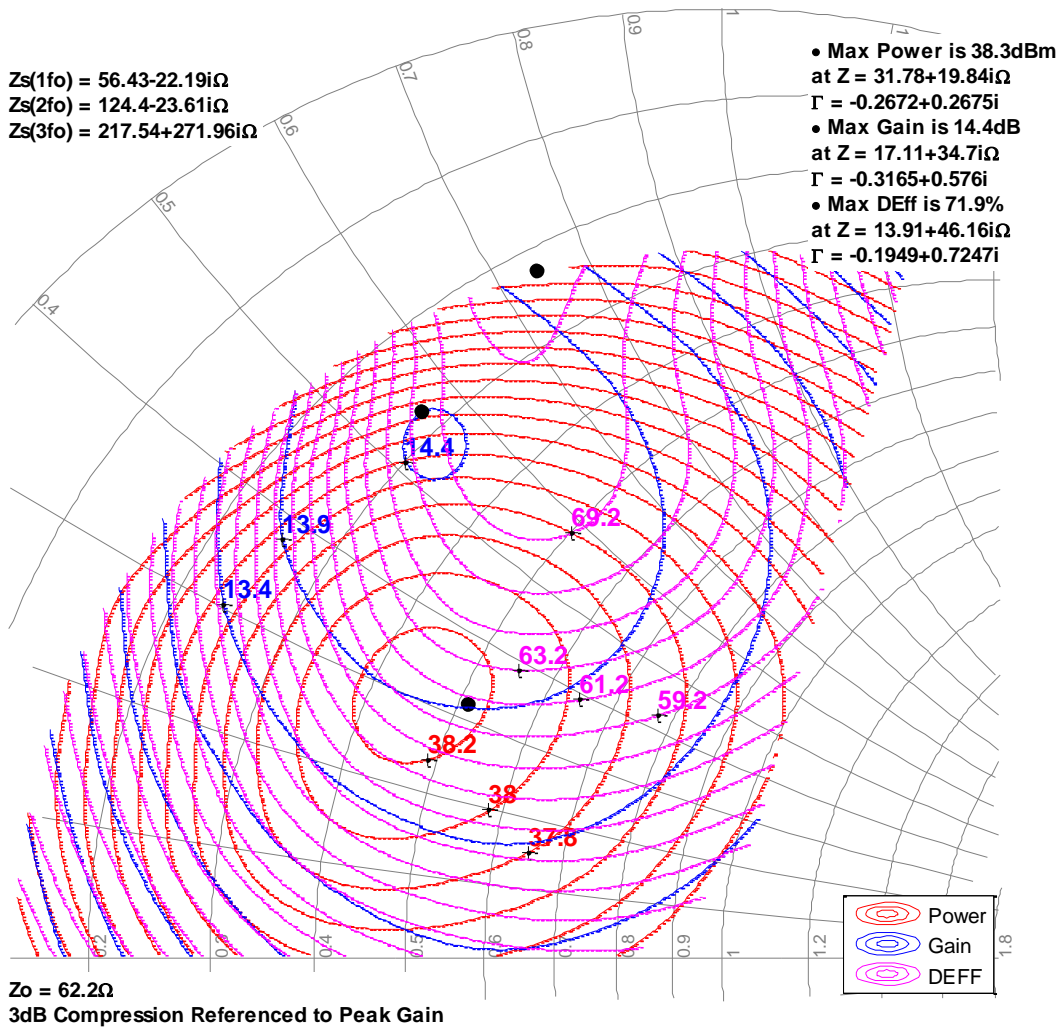
Notes:

1. 32 V, 30 mA, Pulsed signal with 100 uS pulse width and 20% duty cycle. 3 dB compression referenced to peak gain.
2. See page 18 for load pull and source pull reference planes.

Load Pull Smith Charts ^{1, 2}

RF performance that the device typically exhibits when placed in the specified impedance environment. The impedances are not the impedances of the device, they are the impedances presented to the device via an RF circuit or load-pull system. The impedances listed follow an optimized trajectory to maintain high power and high efficiency.

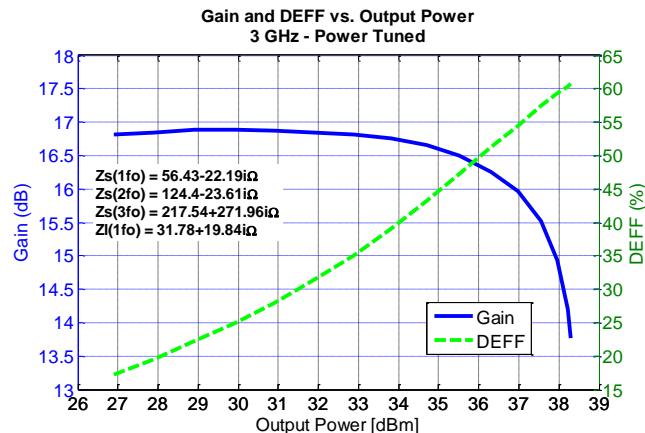
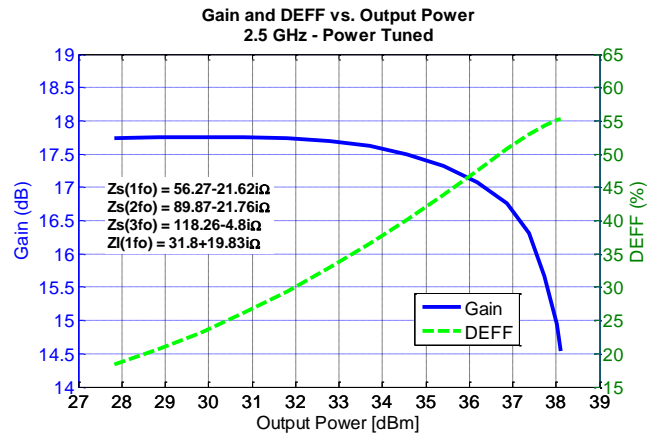
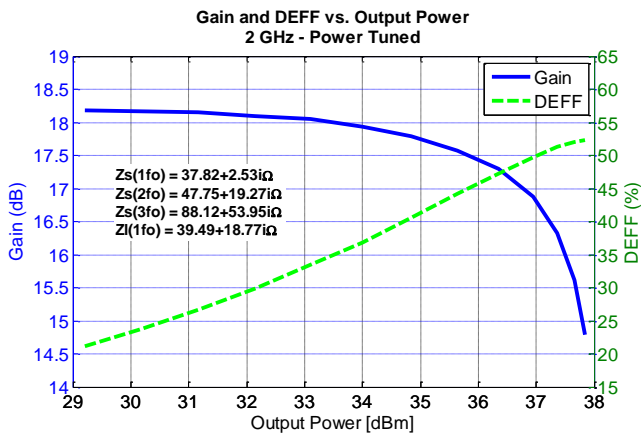
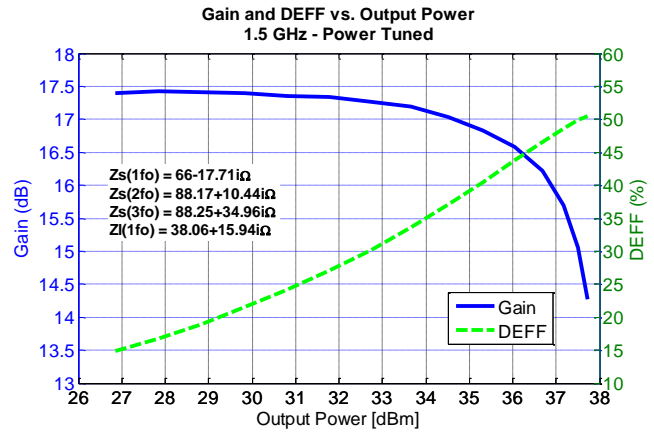
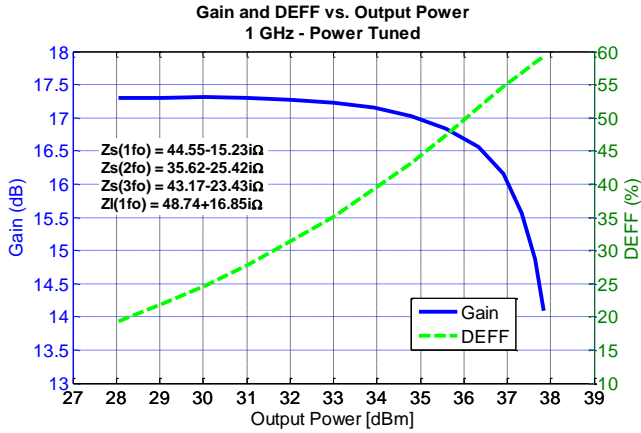
3GHz, Load-pull



Notes:

1. 32 V, 30 mA, Pulsed signal with 100 uS pulse width and 20% duty cycle. 3 dB compression referenced to peak gain.
2. See page 18 for load pull and source pull reference planes.

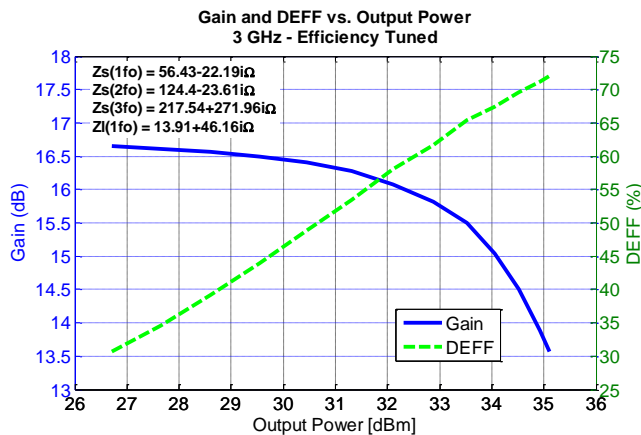
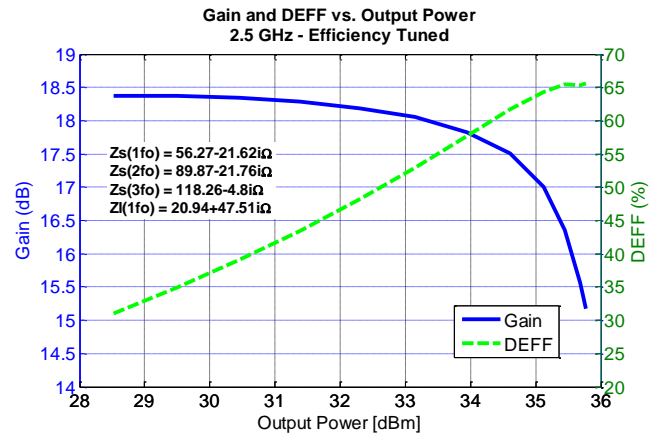
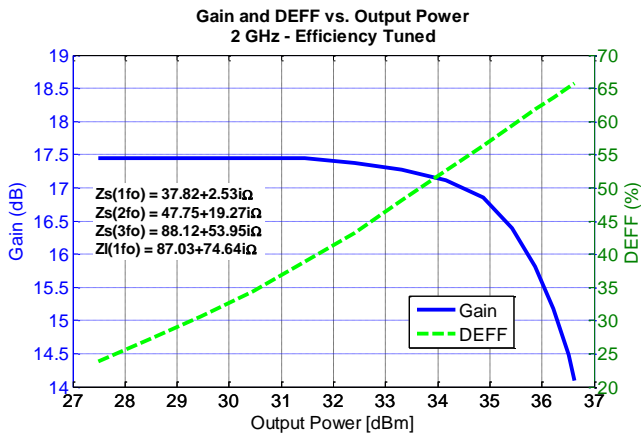
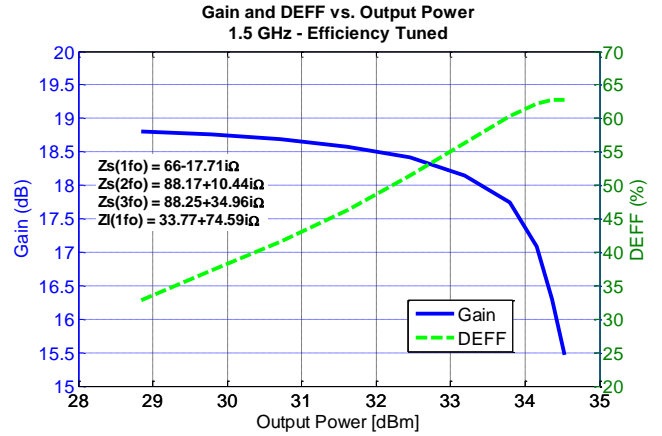
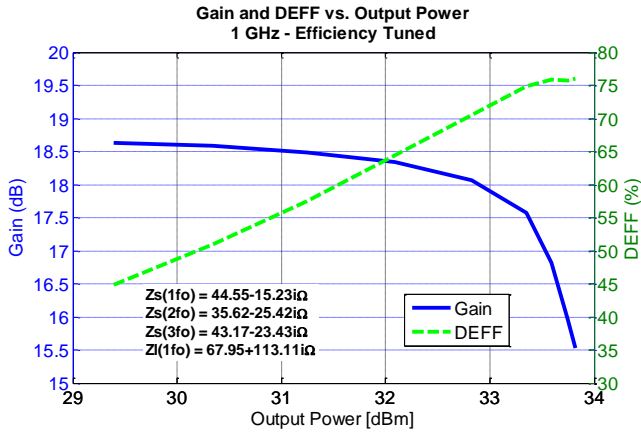
Typical Performance—Power Tuned ^{1,2}



Notes:

1. Pulsed signal with 100uS pulse width and 20% duty cycle
2. See page 18 for load pull and source pull reference planes where the performance was measured.

Typical Performance—Efficiency Tuned ^{1,2}

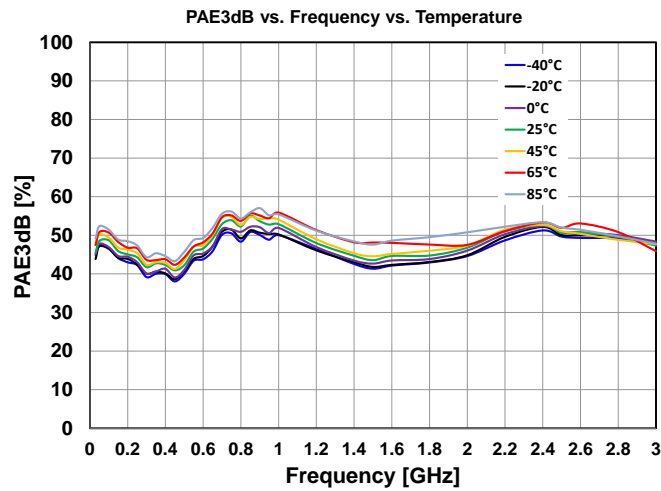
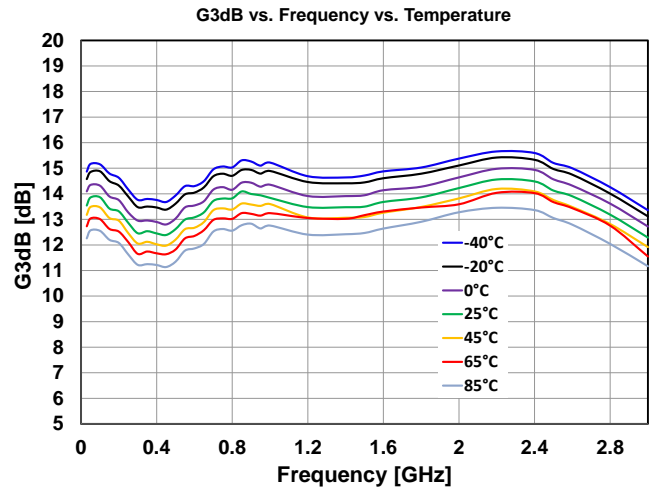
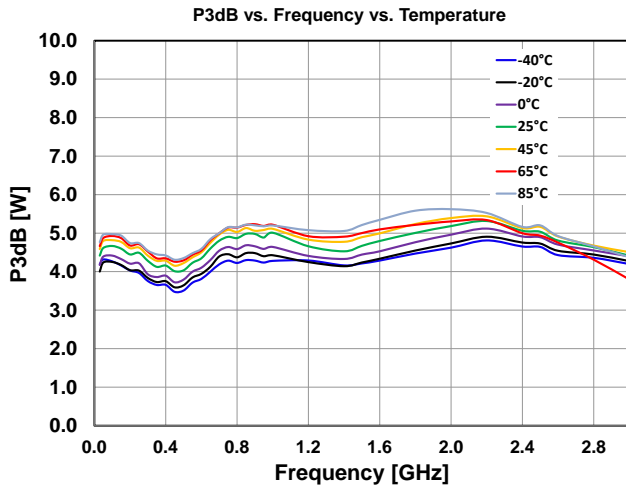


Notes:

1. Pulsed signal with 100uS pulse width and 20% duty cycle
2. See page 18 for load pull and source pull reference planes where the performance was measured.

0.03–3 GHz Evaluation Board Performance Over Temperature^{1, 2}

Performance measured on Qorvo’s 0.03 GHz to 3 GHz Evaluation Board.

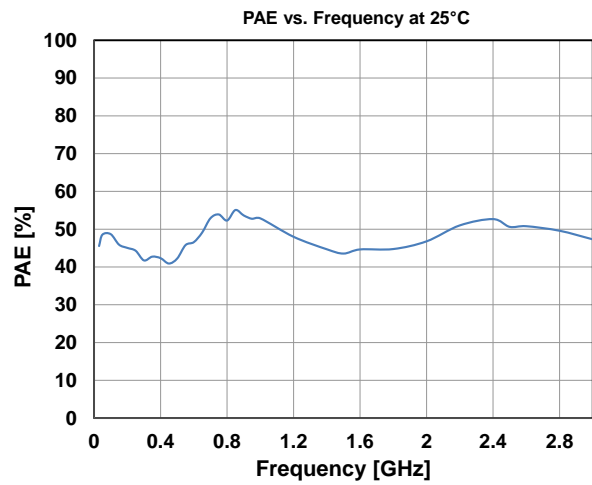
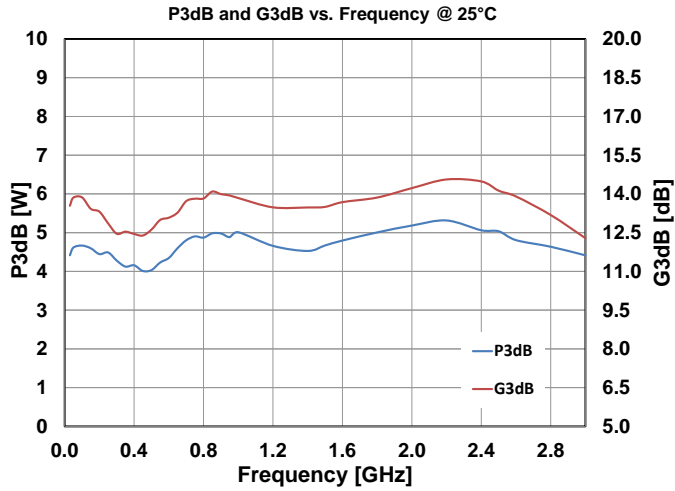


Notes:

1. Test Conditions: $V_{DS} = 32\text{ V}$, $I_{DQ} = 30\text{ mA}$
2. Test Signal: Pulse Width = 100 μs , Duty Cycle = 20%

0.03–3 GHz Evaluation Board Performance At 25 °C^{1,2} – Pulsed

Performance measured on Qorvo's 0.03 GHz to 3 GHz Evaluation Board.

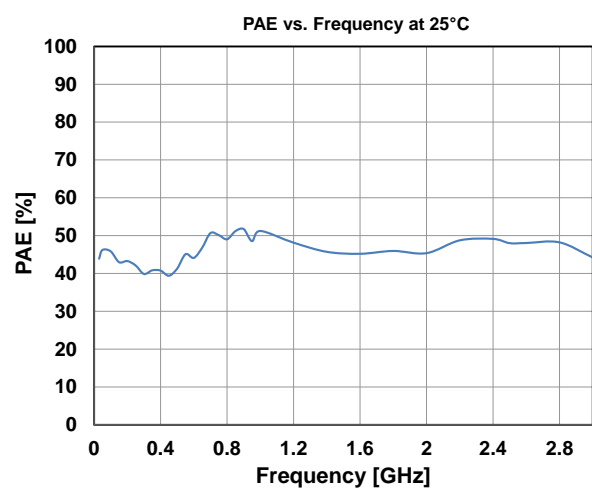
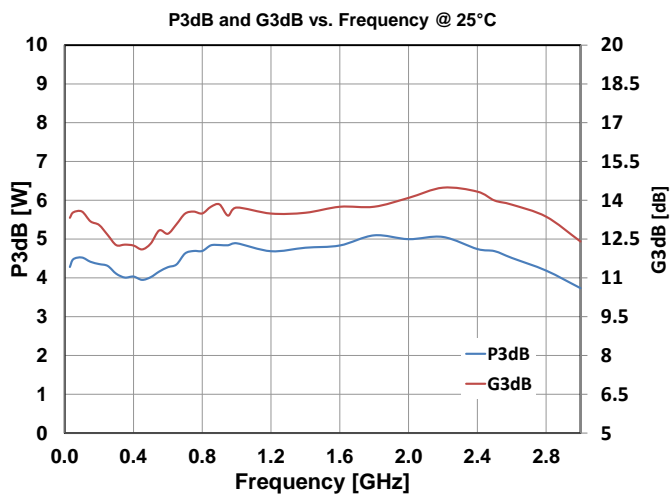


Notes:

1. Test Conditions: $V_{DS} = 32\text{ V}$, $I_{DQ} = 30\text{ mA}$, 25 °C
2. Test Signal: Pulse Width = $100\text{ }\mu\text{s}$, Duty Cycle = 20%

0.03–3 GHz Evaluation Board Performance At 25 °C¹ – CW

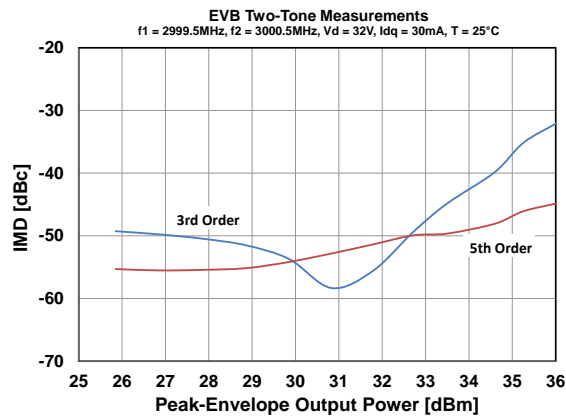
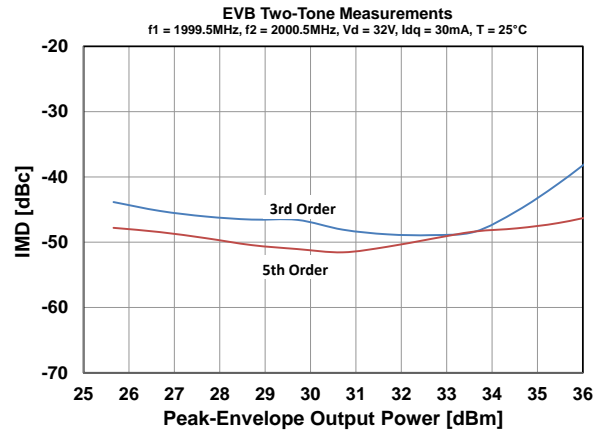
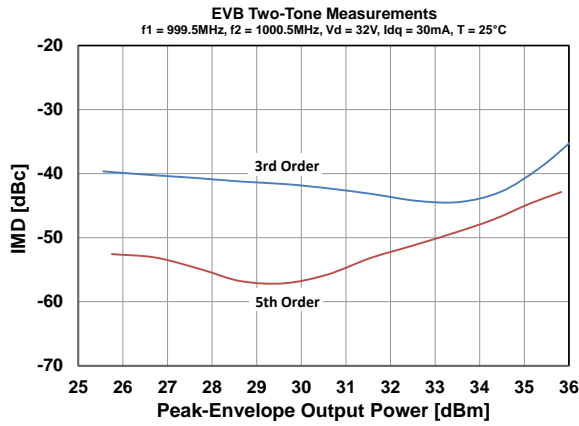
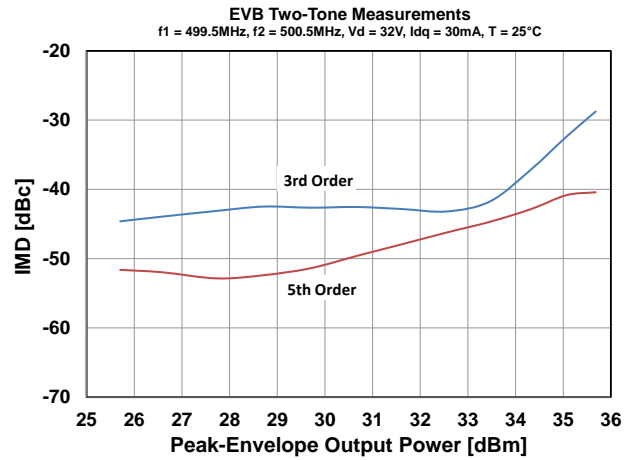
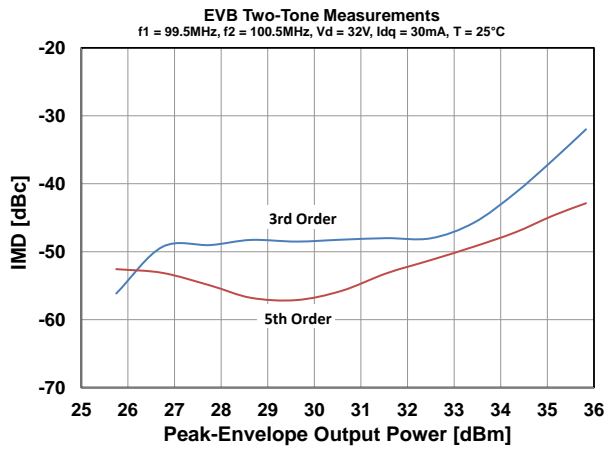
Performance measured on Qorvo's 0.03 GHz to 3 GHz Evaluation Board.



Notes:

1. Test Conditions: $V_{DS} = 32\text{ V}$, $I_{DQ} = 30\text{ mA}$, 25 °C

0.03 – 3 GHz Evaluation Board Performance–Two-Tone Measurements ¹

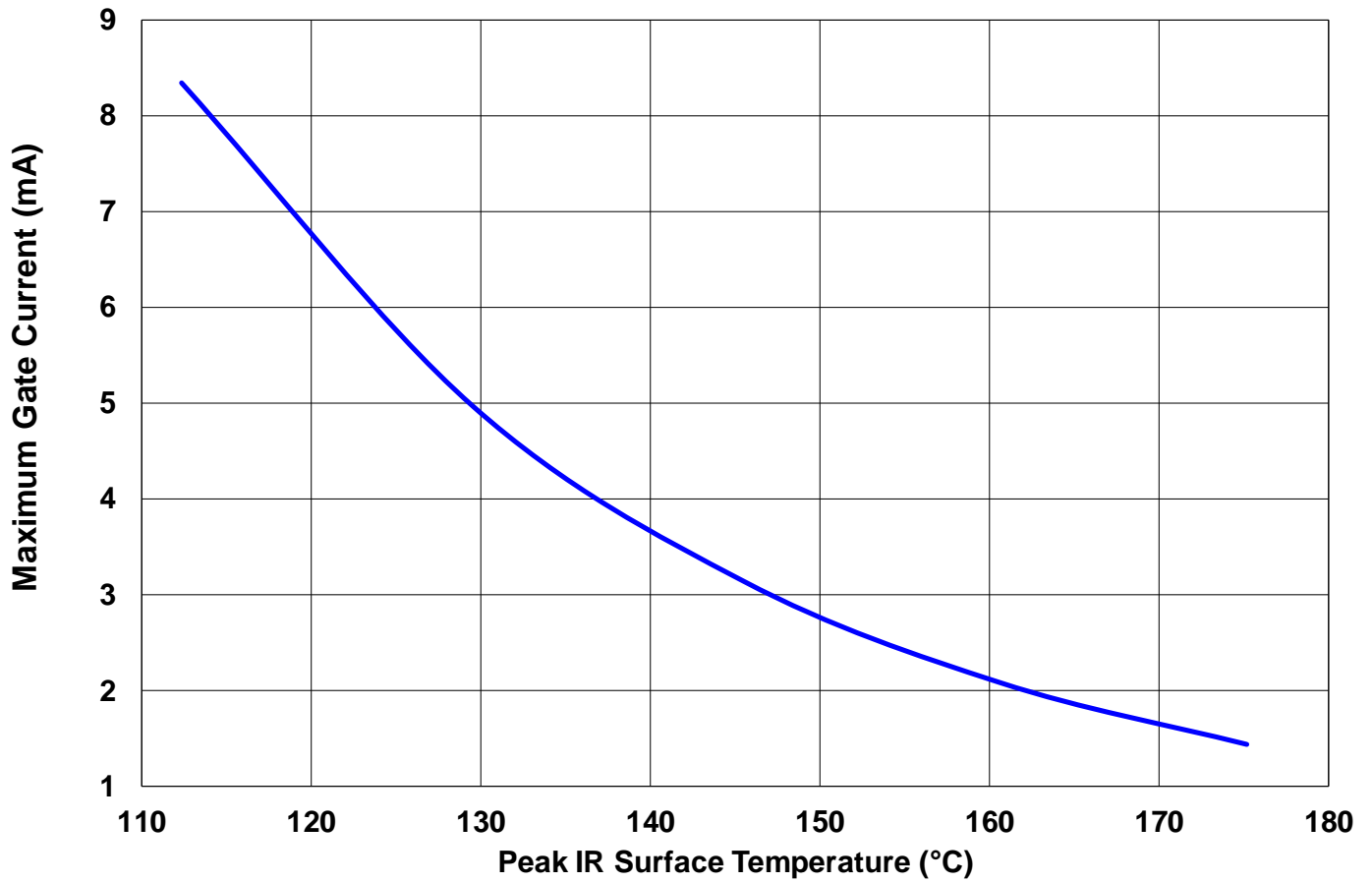


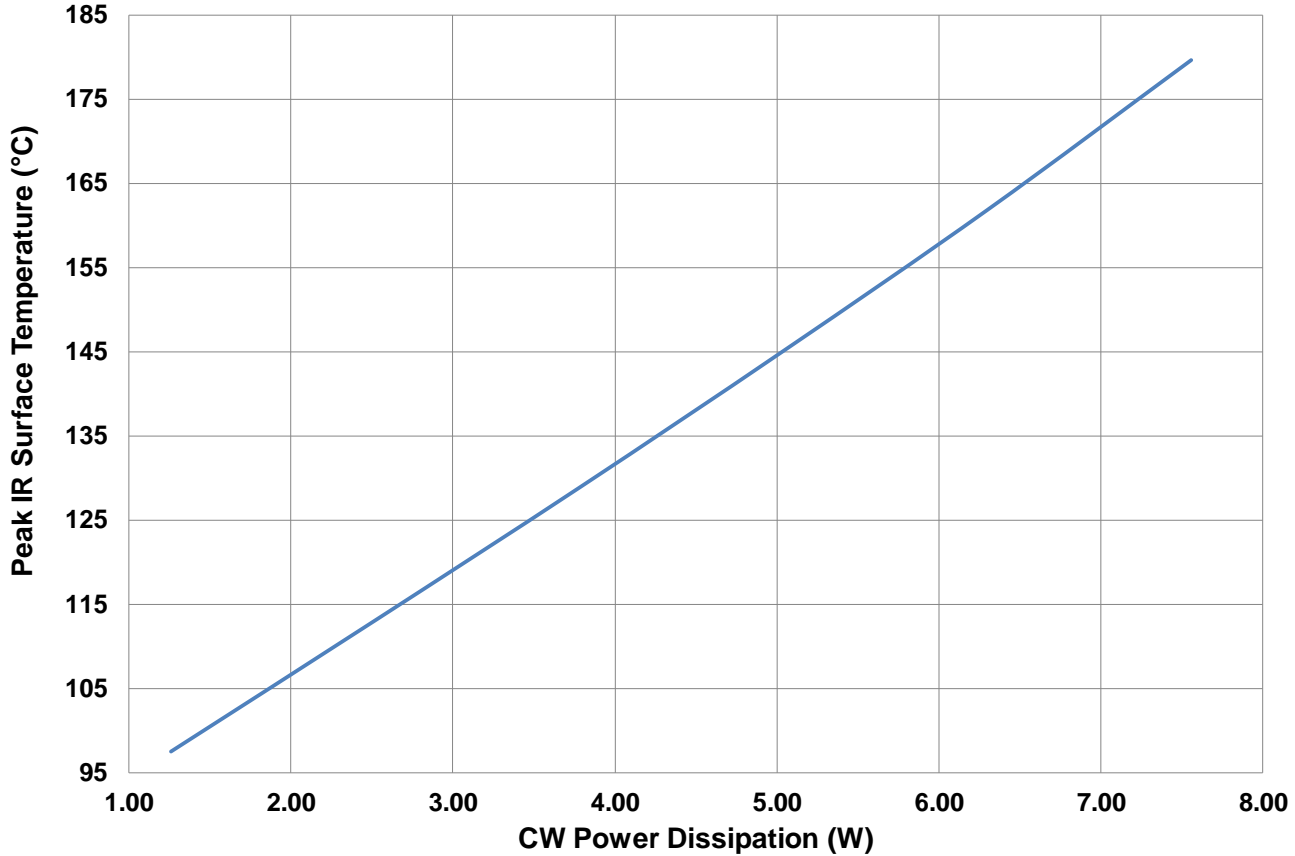
Notes:

1. The Intermodulation Distortion products (IMD) are referenced to peak-envelope output power, which is 6 dB above single-tone output power

Maximum Gate Current

Maximum Gate Current Vs. Peak IR Surface Temperature



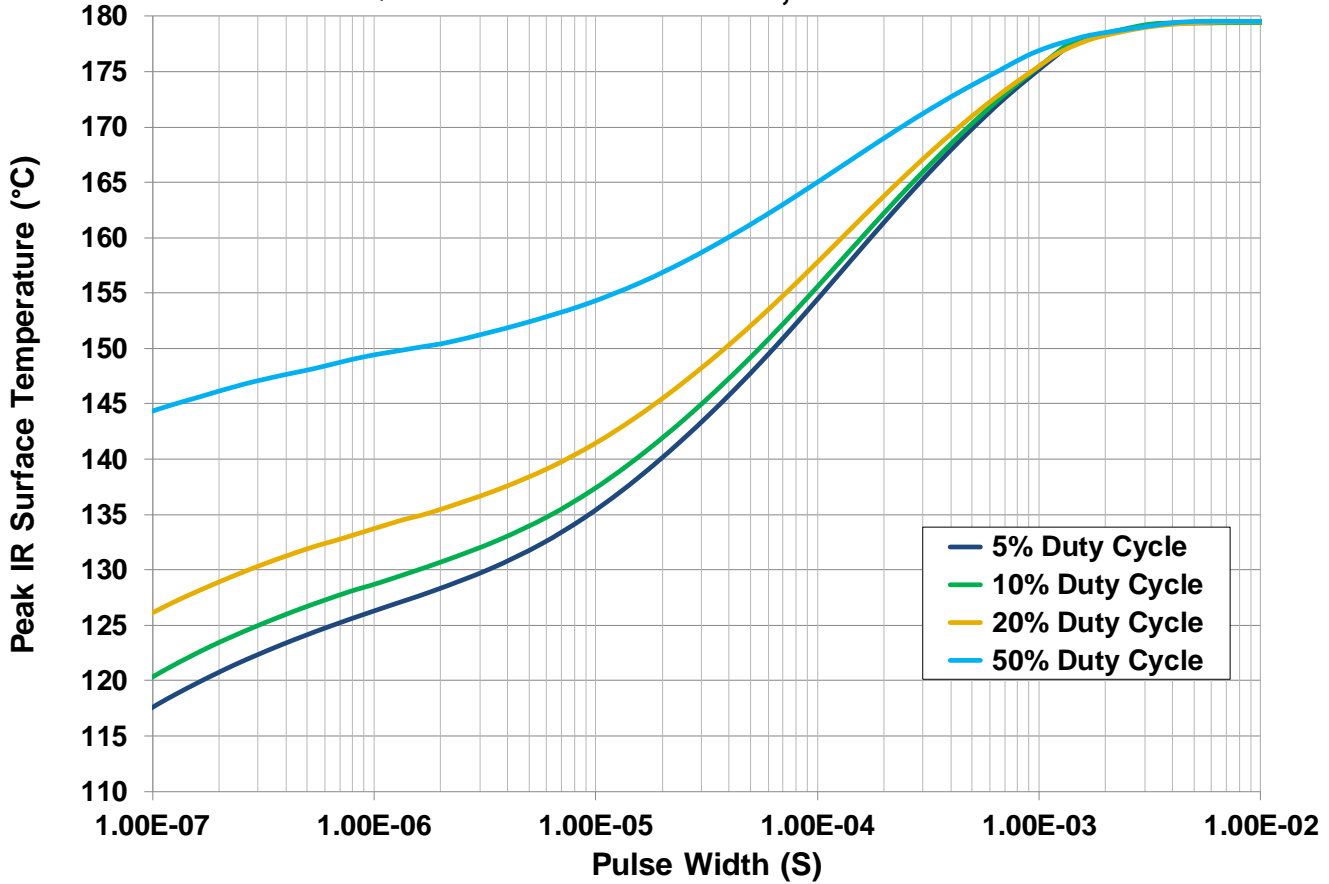
Thermal and Reliability Information - CW
**Peak IR Surface Temperature vs. CW Power Dissipation
Backside of QFN base fixed at 85 °C**


| Parameter | Conditions | Values | Units |
|---|------------------|--------|-------|
| Thermal Resistance, IR ¹ (θ_{JC}) | 85 °C Case | 9.9 | °C/W |
| Peak IR Surface Temperature ¹ (T_{CH}) | 1.26 W Pdiss, CW | 97.4 | °C |
| Thermal Resistance, IR ¹ (θ_{JC}) | 85 °C Case | 11.1 | °C/W |
| Peak IR Surface Temperature ¹ (T_{CH}) | 2.52 W Pdiss, CW | 113 | °C |
| Thermal Resistance, IR ¹ (θ_{JC}) | 85 °C Case | 11.6 | °C/W |
| Peak IR Surface Temperature ¹ (T_{CH}) | 3.78 W Pdiss, CW | 129 | °C |
| Thermal Resistance, IR ¹ (θ_{JC}) | 85 °C Case | 11.9 | °C/W |
| Peak IR Surface Temperature ¹ (T_{CH}) | 5.04 W Pdiss, CW | 145 | °C |
| Thermal Resistance, IR ¹ (θ_{JC}) | 85 °C Case | 12.2 | °C/W |
| Peak IR Surface Temperature ¹ (T_{CH}) | 6.30 W Pdiss, CW | 162 | °C |
| Thermal Resistance, IR ¹ (θ_{JC}) | 85 °C Case | 12.5 | °C/W |
| Peak IR Surface Temperature ¹ (T_{CH}) | 7.56 W Pdiss, CW | 180 | °C |

¹Refer to the following document [GaN Device Channel Temperature, Thermal Resistance, and Reliability Estimates](#)

Thermal and Reliability Information - Pulsed

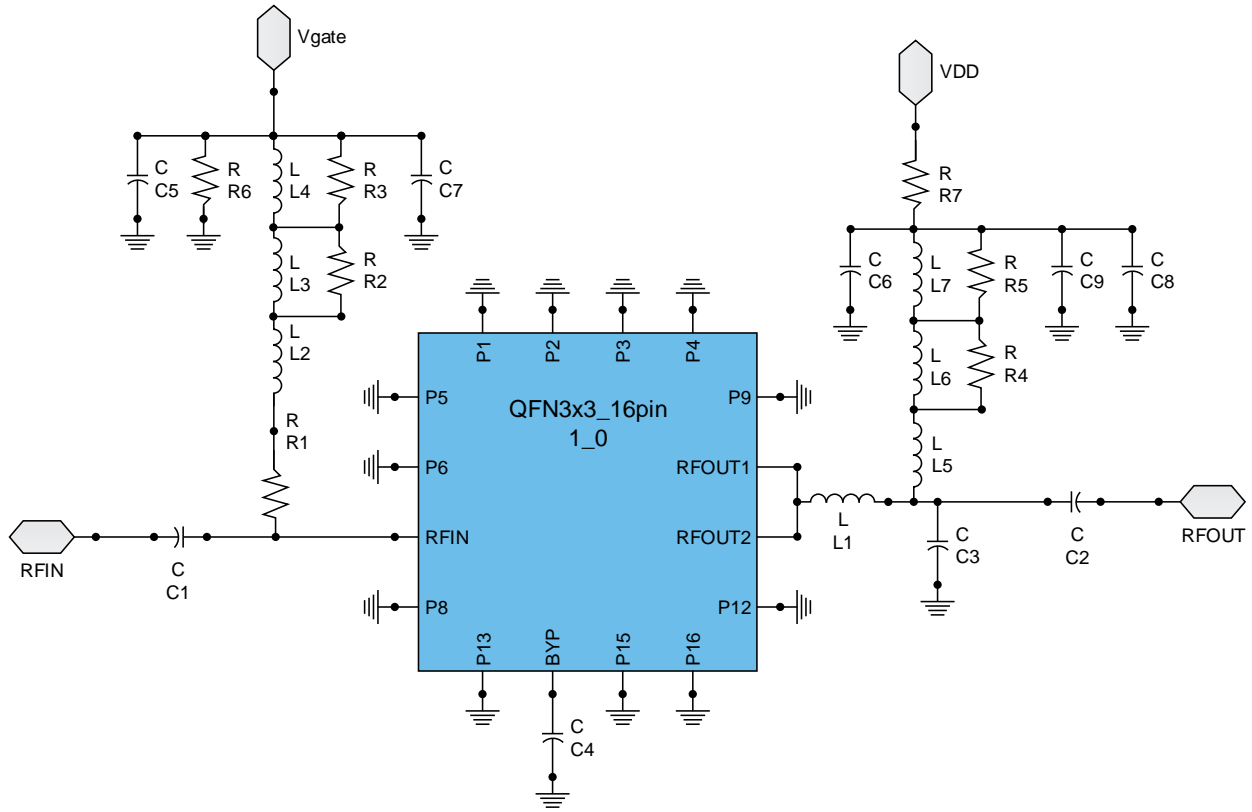
Peak IR Surface Channel Temperature
QFN base fixed at 85 °C, P_{diss} = 7.6 W



| Parameter | Conditions | Values | Units |
|---|--|--------|-------|
| Thermal Resistance, IR ¹ (θ _{JC}) | 85 °C Case | 9.1 | °C/W |
| Peak IR Surface Temperature ¹ (T _{CH}) | 7.6 W P _{diss} , 100 uS Pulse Width, 5% DC | 154 | °C |
| Thermal Resistance, IR ¹ (θ _{JC}) | 85 °C Case | 9.3 | °C/W |
| Peak IR Surface Temperature ¹ (T _{CH}) | 7.6 W P _{diss} , 100 uS Pulse Width, 10% DC | 156 | °C |
| Thermal Resistance, IR ¹ (θ _{JC}) | 85 °C Case | 9.6 | °C/W |
| Peak IR Surface Temperature ¹ (T _{CH}) | 7.6 W P _{diss} , 100 uS Pulse Width, 20% DC | 158 | °C |
| Thermal Resistance, IR ¹ (θ _{JC}) | 85 °C Case | 10.5 | °C/W |
| Peak IR Surface Temperature ¹ (T _{CH}) | 7.6 W P _{diss} , 100 uS Pulse Width, 50% DC | 165 | °C |

¹Refer to the following document [GaN Device Channel Temperature, Thermal Resistance, and Reliability Estimates](#)

0.03–3 GHz Application Circuit



Bias-up Procedure

V_G set to -5 V.

V_D set to 32 V.

Adjust V_G more positive until quiescent I_D is 30 mA.

Apply RF signal.

Bias-down Procedure

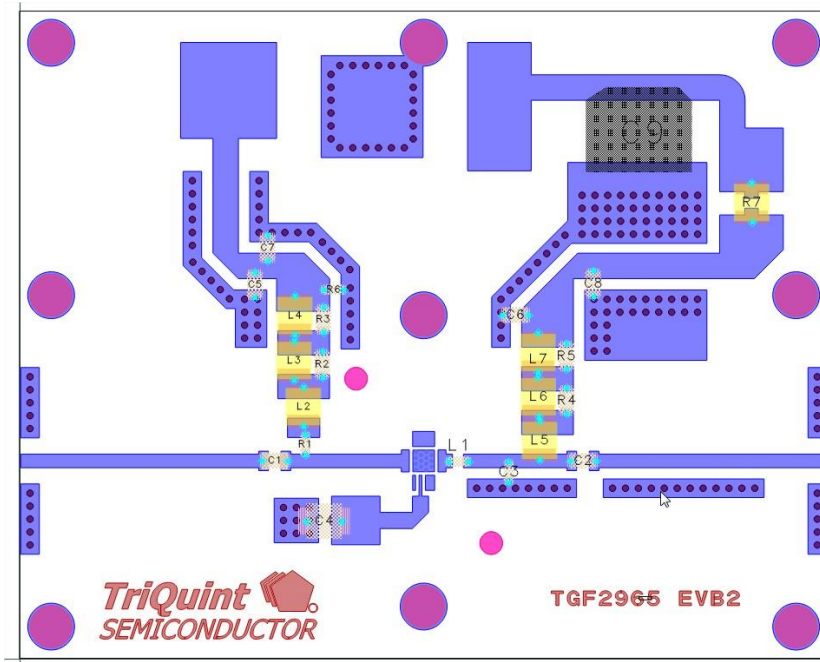
Turn off RF signal

Turn off V_D and wait 1 second to allow drain capacitor dissipation

Turn off V_G

0.03–3 GHz Evaluation Board Layout

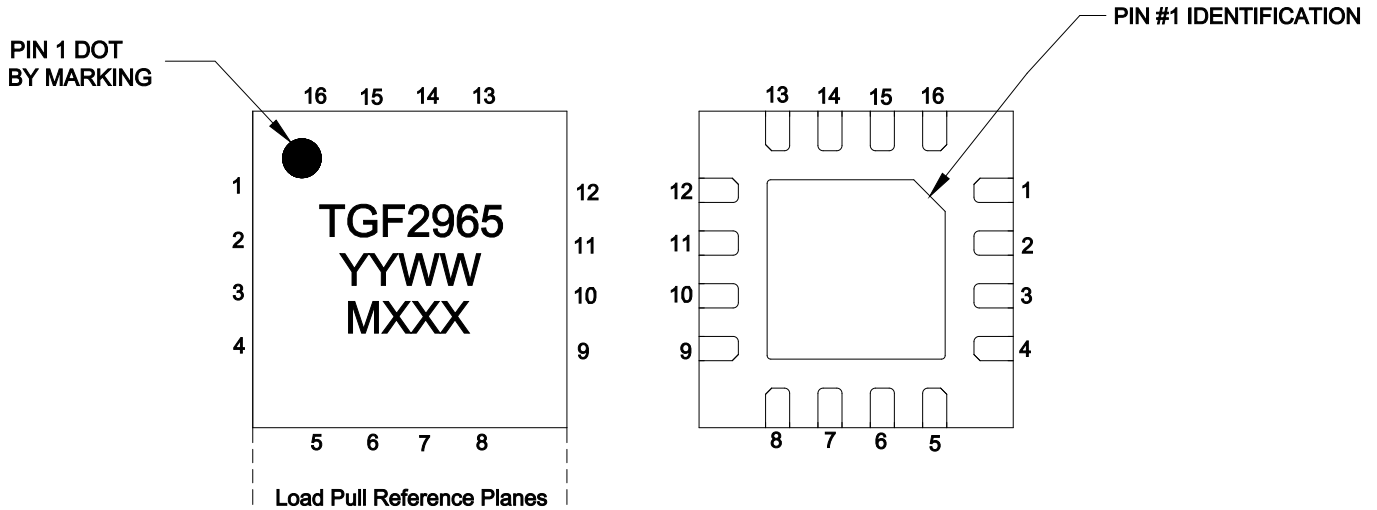
Top RF layer is 0.020" thick Rogers RO4350B, $\epsilon_r = 3.48$. The pad pattern shown has been developed and tested for optimized assembly at Qorvo Semiconductor. The PCB land pattern has been developed to accommodate lead and package tolerances.



00.03–3 GHz EVB Bill of Materials

| Reference Des. | Value | Qty | Manuf. | Part Number |
|----------------|--------------|-----|-----------------|---------------------|
| C1, C2, C5, C6 | 2400 pF | 4 | DLI | C08BL102X-1UN-X0T |
| C3 | 0.2 pF | 1 | Murata | GRM1555C1HR20BZ01 |
| C4, C7 | 10 uF | 2 | TDK | C1632X5R0J106M130AC |
| C8 | 1 uF | 1 | AVX | 18121C105KAT2A |
| C9 | 220 uF | 1 | United Chemicon | EMVY500ADA221MJA0G |
| L1 | 2 nH | 1 | CoilCraft | 0603HC-2N0XJLU |
| L2, L5 | 82 nH | 2 | CoilCraft | 1008CS-820XGLB |
| L3, L6 | 100 nH | 2 | CoilCraft | 1008CS-101XGLB |
| L4, L7 | 900 nH | 2 | CoilCraft | 1008AF-901XJLB |
| R1 | 499 Ω | 1 | Venkel | CR0603-10W-4990FT |
| R2, R3, R4, R5 | 400 Ω | 4 | Venkel | CR0805-8W-4020FT |
| R6 | 1 k Ω | 1 | Venkel | CR0603-10W-1001FT |
| R7 | 0 Ω | DNP | | |

Pin Layout



Pin Description

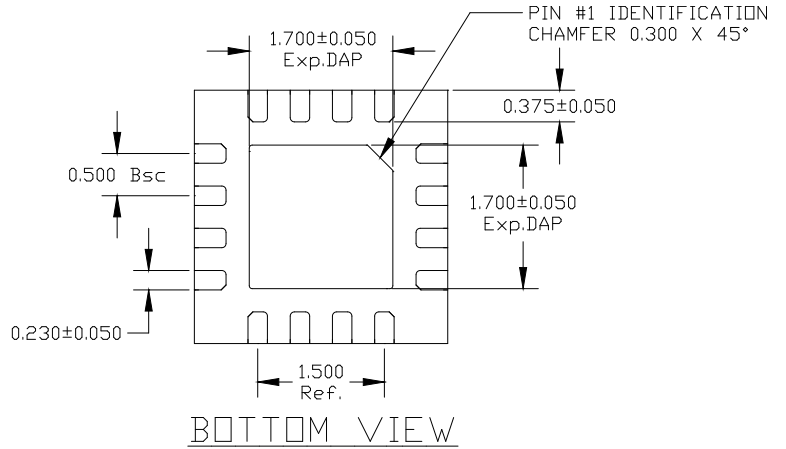
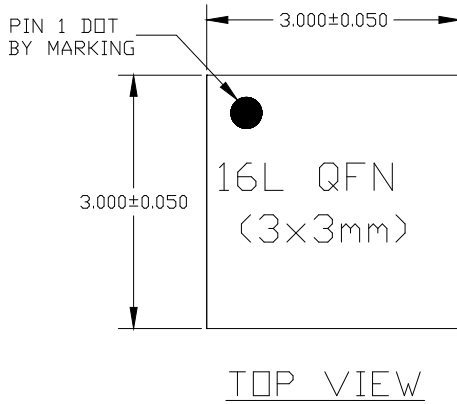
| Pin Number | Symbol | Description |
|------------|---------------|--|
| 10, 11 | V_D /RF OUT | Drain voltage / RF Output to be matched to 50 ohms; see EVB Layout on page 19 as an example. |
| 3 | V_G /RF IN | Gate voltage / RF Input to be matched to 50 ohms; see EVB Layout on page 19 as an example. |
| 6 | Off-chip Cap | Off-chip capacitor to extend low-frequency gain |
| Back side | Source | Source connected to ground |

Notes:

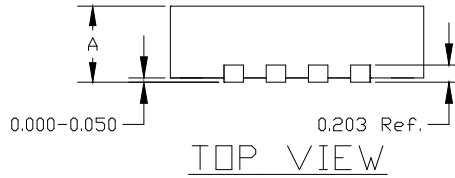
1. Thermal resistance measured to back side of package.
2. The TGF2965-SM will be marked with the “TGF2965” designator and a lot code marked below the part designator. The “YY” represents the last two digits of the calendar year the part was manufactured, the “WW” is the work week of the assembly lot start, and the “MXXX” is the production lot number.

Mechanical Information

All dimensions are in millimeters.



| | | | |
|---|------|-----|-------|
| A | MAX. | SLP | 0.900 |
| | NOM. | | 0.850 |
| | MIN. | | 0.800 |



Note:

1. Unless otherwise noted, all dimension tolerances are +/-0.127 mm.
2. This package is lead-free/RoHS-compliant. The plating material on the leads is NiAu. It is compatible with both lead-free (maximum 260 °C reflow temperature) and tin-lead (maximum 245 °C reflow temperature) soldering processes

Recommended Soldering Temperature Profile

